


<b>Search Notes</b>  	<b>Application/Control No.</b>  10671548	<b>Applicant(s)/Patent Under Reexamination</b>  MURAKAWA, AKIRA
	<b>Examiner</b>  Nguyen, Khoi	<b>Art Unit</b>  2132

SEARCHED			
Class	Subclass	Date	Examiner
713	156, 173	9/24/2008	JKG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST - USPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	9/24/2008	JKG
PALM - Inventor Name Search	9/24/2008	JKG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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